


<b>Search Notes</b>  	<b>Application/Control No.</b>  10690330	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  Feben M Haile	<b>Art Unit</b>  2616

### SEARCHED

Class	Subclass	Date	Examiner
370	392, 395.51, 395.53, 466, 469, 471, 474	3/12/2008	FH
398	45, 58, 63	3/12/2008	FH
710	30	3/12/2008	FH

### SEARCH NOTES

Search Notes	Date	Examiner
mac, frame, ethernet, optical, pon, epon, llid, tag, label, identifier, physical layer, data layer, olt, onu, add, tag, reconfigure, append, affix, annex, flag, field, insert, stack	3/12/2008	FH

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner